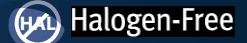


EPC2121 – Bidirectional eGaN® Power Switch

 $V_{DD}, 100\text{ V}$
 $R_{DD(on)}, 50\text{ m}\Omega\text{ typ}$
 $I_D, 2.5\text{ A}$


Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source



| Maximum Ratings | | | |
|-----------------|---|------------|------|
| PARAMETER | | VALUE | UNIT |
| V_{DD} | Drain-to-Drain Voltage (Continuous) | 100 | V |
| | Drain-to-Drain Voltage (up to 10,000 5 ms pulses at 150 °C) | 120 | |
| V_{DS} | Drain-to-Source Voltage (Continuous) | 100 | V |
| | Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150 °C) | 120 | |
| I_D | Continuous ($T_A = 25\text{ °C}$) | 2.5 | A |
| | Pulsed ($25\text{ °C}, T_{PULSE} = 300\text{ }\mu\text{s}$) | 18 | |
| V_{GD} | Gate-to-Drain Voltage | 6 | V |
| | Gate-to-Drain Voltage | -100 | |
| V_{GS} | Gate-to-Source Voltage | 6 | |
| | Gate-to-Source Voltage | -4 | |
| T_J | Operating Temperature | -40 to 150 | °C |
| T_{STG} | Storage Temperature | -40 to 150 | |

| Thermal Characteristics | | | |
|-------------------------|---|-----|------|
| PARAMETER | | TYP | UNIT |
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case (Case TOP) | 4.8 | °C/W |
| $R_{\theta JB}$ | Thermal Resistance, Junction-to-Board (Case BOTTOM) | 18 | |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | 100 | |

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details

| Static Characteristics ($T_J = 25\text{ °C}$ unless otherwise stated) | | | | | | |
|--|-------------------------------|--|-----|-----|-----|---------------|
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| BV_{DDs} | Drain-to-Drain Voltage | $V_{GD1(D2)S} = 0\text{ V}, I_{D1(D2)S} = 10\text{ }\mu\text{A}$, source tied to one drain terminal | 100 | | | V |
| I_{DDs} | Drain-Drain Leakage | $V_{D1(D2)S} = 80\text{ V}, V_{GD1(D2)} = 0\text{ V}$, source tied to one drain terminal | | 0.1 | 10 | μA |
| I_{GD} | Gate-to-Drain Forward Leakage | $V_{GD1(D2)} = 5\text{ V}$, source tied to one drain terminal | | 0.8 | 200 | |
| | Gate-to-Drain Reverse Leakage | $V_{GD1(D2)} = -80\text{ V}$, source tied to one drain terminal | | 0.1 | 7 | |
| $V_{GS(TH)}$ | Gate Threshold Voltage | $V_{D1(D2)S} = V_{GS}, I_{D1(D2)} = 0.7\text{ mA}$, source tied to one drain terminal | 0.8 | 1.2 | 2.5 | V |
| $R_{DD(on)}$ | Drain-Drain On Resistance | $V_{GS} = 5\text{ V}, I_D = 1\text{ A}$ | | 50 | 78 | m Ω |



Die size: 0.9 x 0.9 mm

EPC2121 eGaN® FETs are supplied in passivated die form with solder bumps.

Applications

- Solid-state relay in a thermostat
- USB PD 3.1 port protection
- Battery and reverse battery protection
- Bidirectional blocking load switch
- RF switch

Benefits

- Bidirectional blocking
- Ultra Small Footprint, 90% smaller than MOSFET alternative
- Lower On-Resistance, 50% lower than two MOSFETs in common source configuration

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2121>

| Dynamic Characteristics# (T _j = 25°C unless otherwise stated) | | | | | | |
|--|---|---|-----|------|-----|------|
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| C _{ISS} | Input Capacitance | V _{DD} = 50 V, V _{GS} = 0 V, Source tied to one drain terminal | | 137 | 218 | pF |
| C _{RSS} | Reverse Transfer Capacitance | | | 1 | | |
| C _{OSS} | Output Capacitance | | | 54 | 63 | |
| C _{OSS(ER)} | Effective Output Capacitance, Energy Related (Note 1) | V _{DD} = 0 to 50 V, V _{GS} = 0 V, Source tied to one drain terminal | | 63 | | |
| C _{OSS(TR)} | Effective Output Capacitance, Time Related (Note 2) | | | 83 | | |
| R _G | Gate Resistance | | | 5.9 | | |
| Q _G | Total Gate Charge | V _{DD} = 50 V, V _{GS} = 5 V, I _D = 1 A, Source tied to one drain terminal | | 1.1 | 1.6 | nC |
| Q _{GS} | Gate-to-Source Charge | V _{DD} = 50 V, I _D = 1 A, Source tied to one drain terminal | | 0.28 | | |
| Q _{GD} | Gate-to-Drain Charge | | | 0.16 | | |
| Q _{G(TH)} | Gate Charge at Threshold | | | 0.21 | | |
| Q _{OSS} | Output Charge | V _{DD} = 50 V, V _{GS} = 0 V, Source tied to one drain terminal | | 4.2 | 5 | |
| Q _{RR} | Source-Drain Recovery Charge | | | 0 | | |

Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 1: C_{OSS(ER)} is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50 V_{DSS}.

Note 2: C_{OSS(TR)} is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50 V_{DSS}.

Figure 1: Typical Output Characteristics at 25°C*

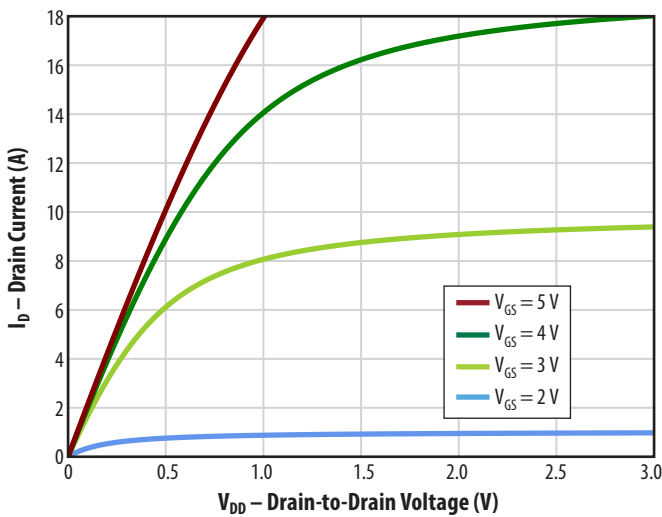


Figure 2: Typical Transfer Characteristics*

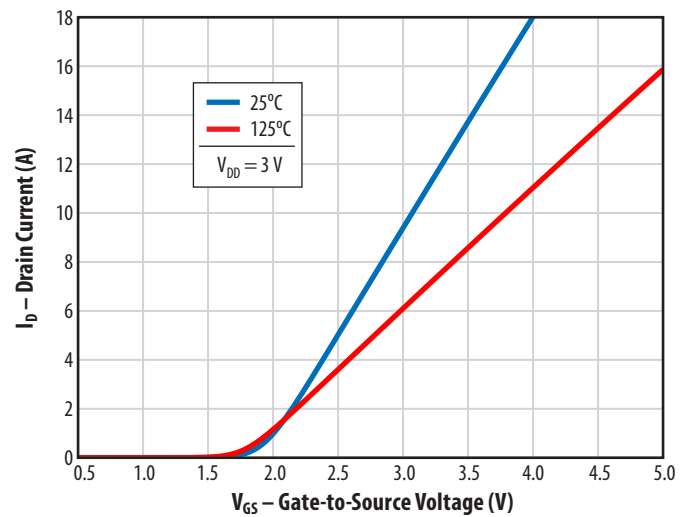


Figure 3: Typical R_{DD(on)} vs. V_{GS} for Various Currents*

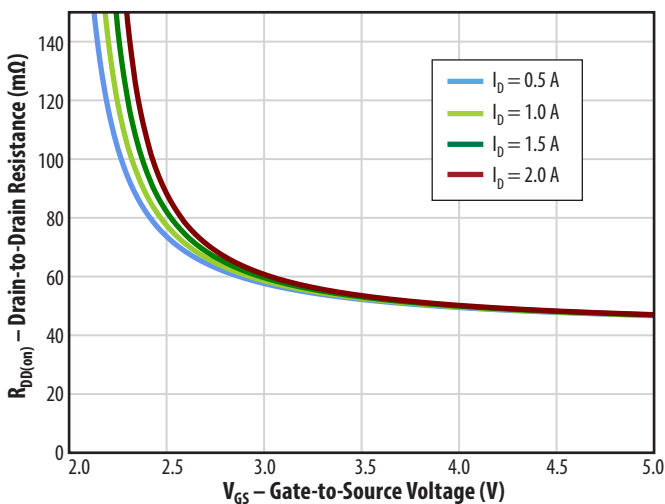
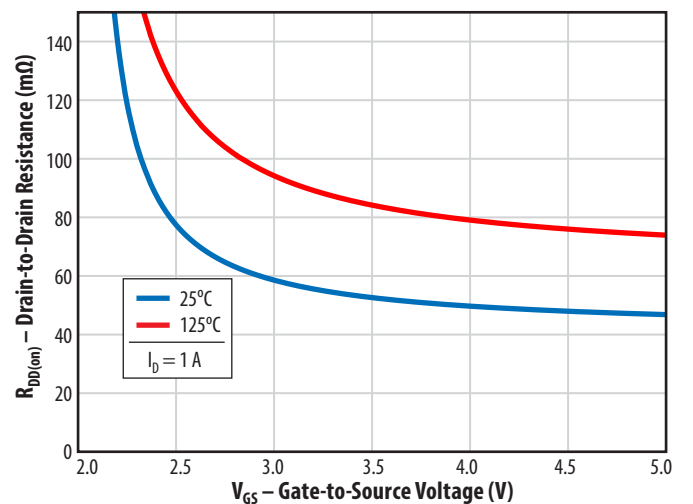


Figure 4: Typical R_{DD(on)} vs. V_{GS} for Various Temperatures*



* Source tied to one drain terminal; drains are symmetrical. See Figure 13.

Figure 5a: Typical Capacitance (Linear Scale)*

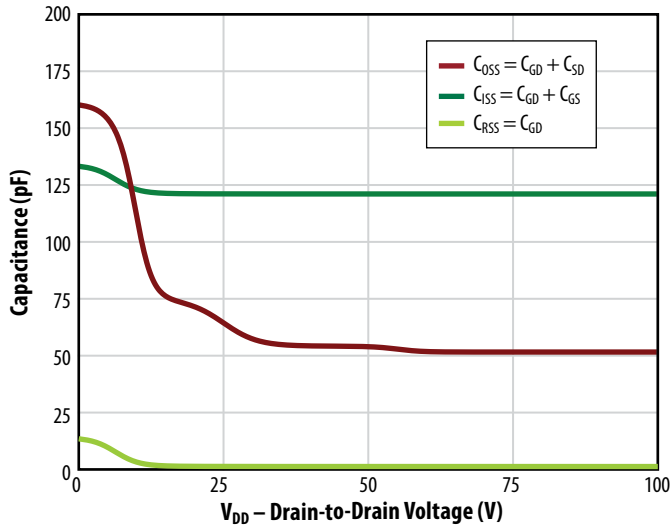


Figure 5b: Typical Capacitance (Log Scale)*

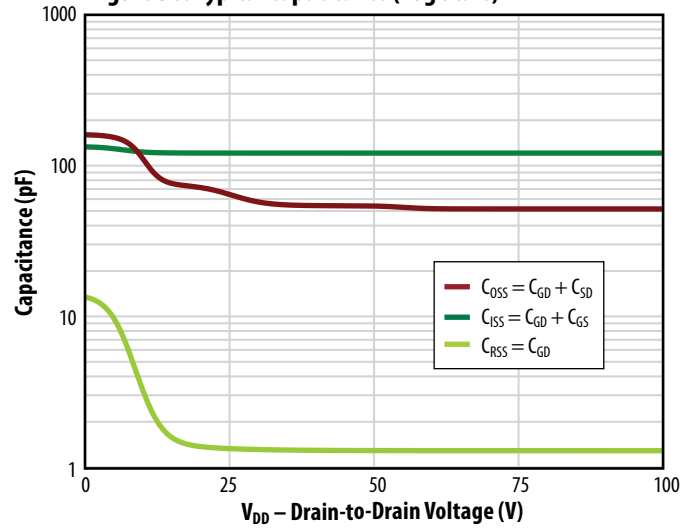


Figure 6: Typical Output Charge and Coss Stored Energy*

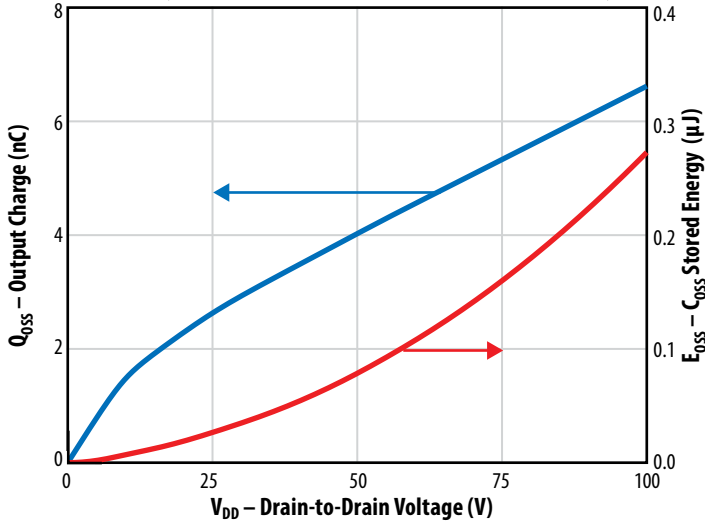


Figure 7: Typical Gate Charge*

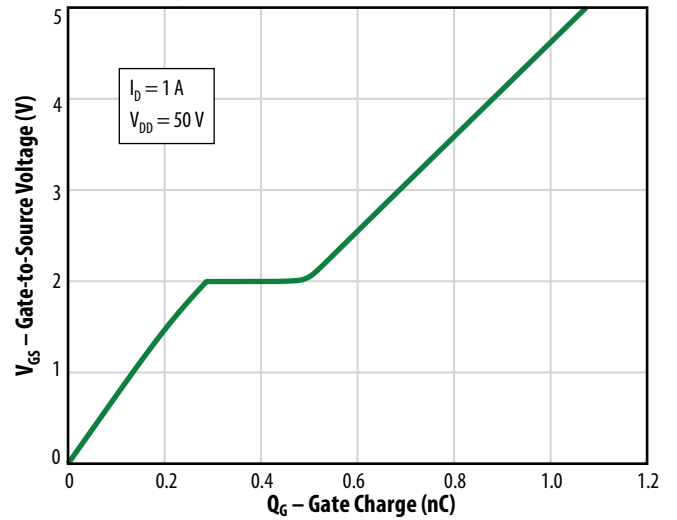
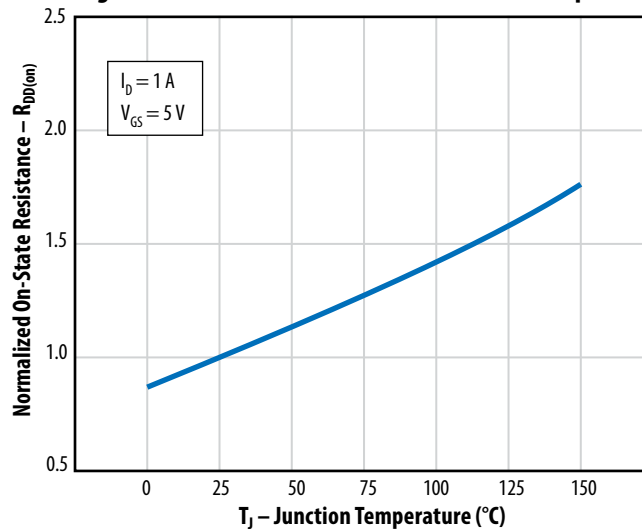


Figure 8: Normalized On-State Resistance vs. Temperature*



* Source tied to one drain terminal; drains are symmetrical. See Figure 13.

Figure 9: Normalized Threshold Voltage vs. Temperature*

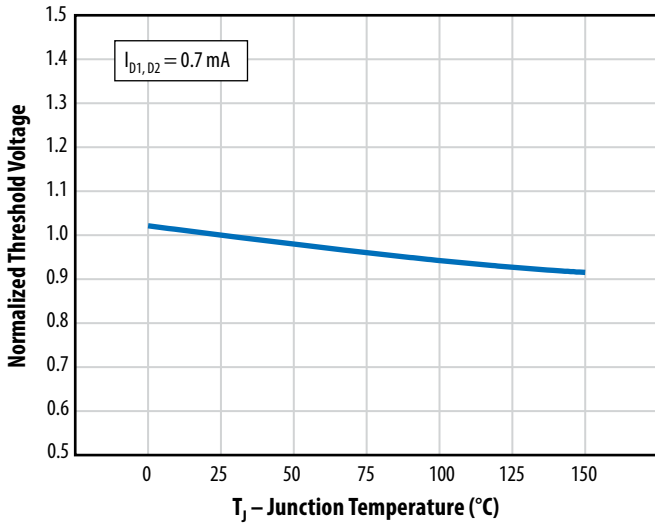


Figure 10: Safe Operating Area*

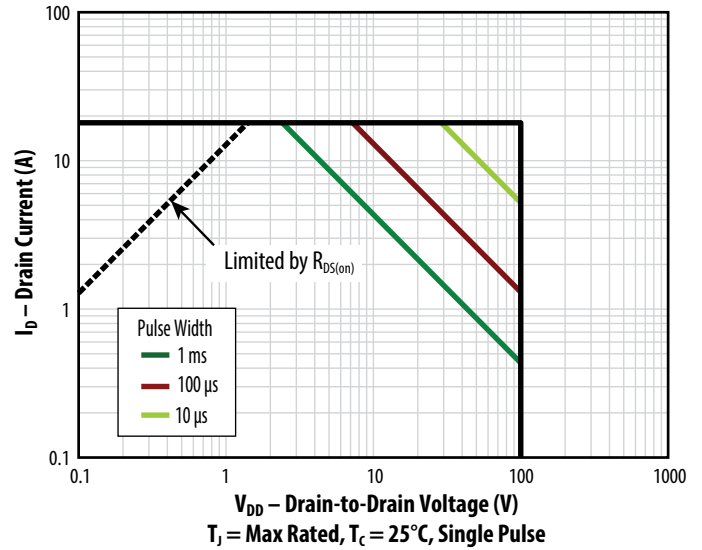


Figure 11: Typical Transient Thermal Response Curves

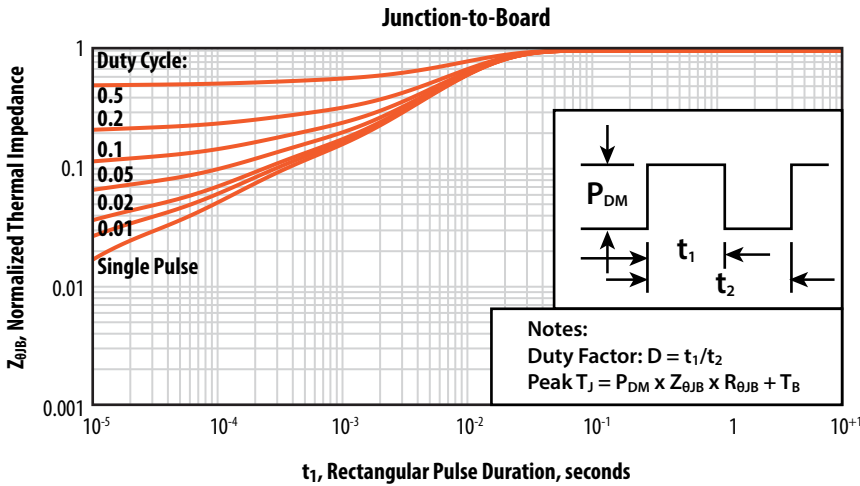


Figure 12: Application configuration

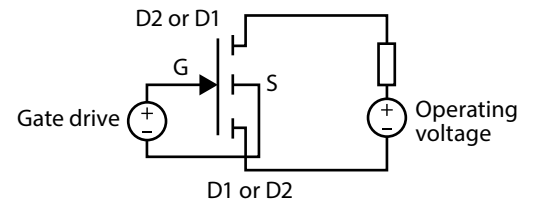
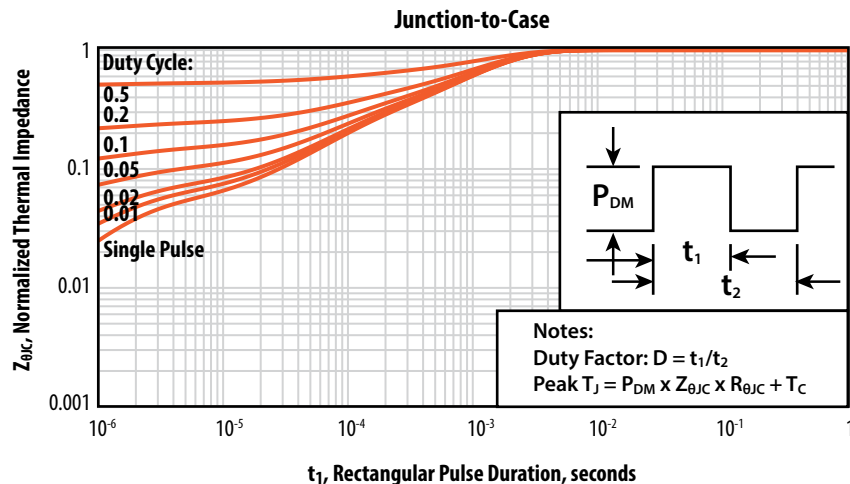
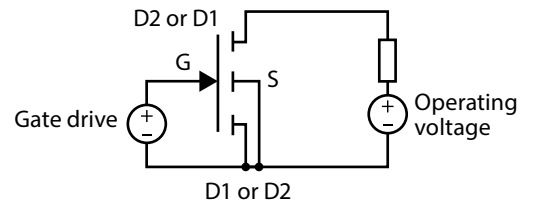


Figure 13: Test circuit



TYPICAL THERMAL CONCEPT

The EPC2121 can take advantage of dual sided cooling to maximize its heat dissipation capabilities in high power density designs. **Note that the top of EPC FETs are connected to source potential, so for half-bridge topologies the Thermal Interface Material (TIM) needs to provide electrical isolation to the heatsink.**

Recommended best practice thermal solutions are covered in detail in [How2AppNote012 - How to Get More Power Out of an eGaN Converter.pdf](#).

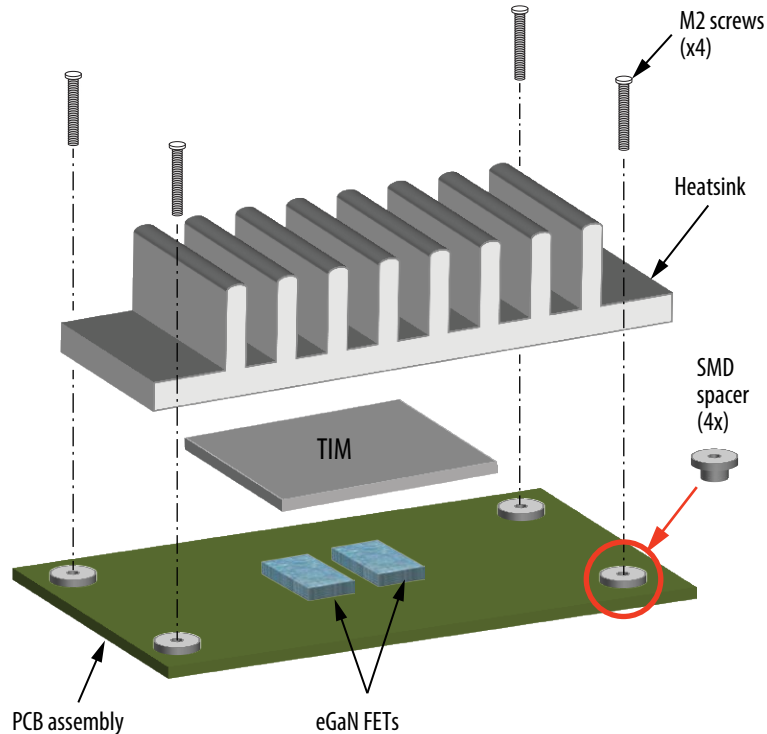


Figure 14: Exploded view of heatsink assembly using screws

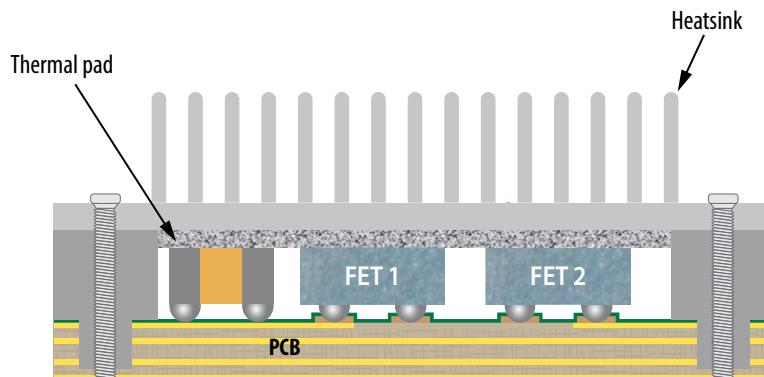


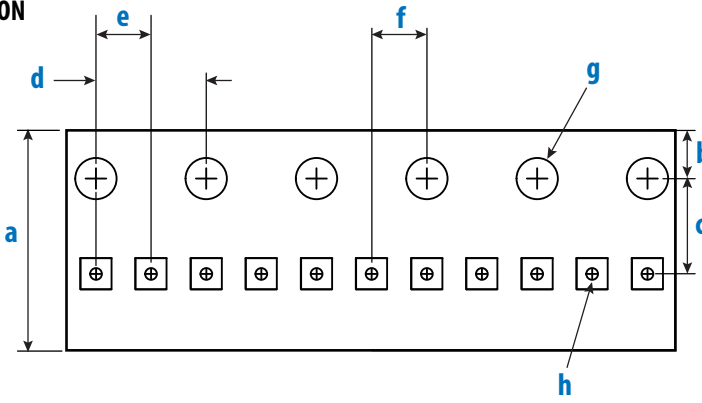
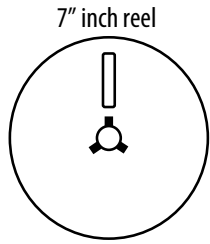
Figure 15: A cross-section image of dual sided thermal solution

Note: Connecting the heatsink to ground is recommended and can significantly improve radiated EMI

The thermal design can be optimized by using the [GaN FET Thermal Calculator](#) on EPC's website.

TAPE AND REEL CONFIGURATION

2 mm pitch, 8 mm wide tape on 7" reel



Loaded Tape Feed Direction →



Die orientation dot
Pin 1 is under this corner

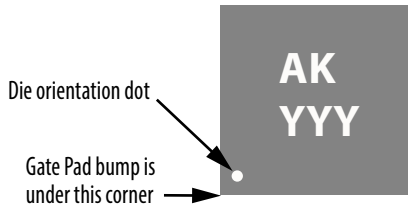
Die is placed into pocket solder bump side down (face side down)

| EPC2121 (Note 1) | Dimension (mm) | | |
|-------------------|----------------|------|------|
| | Target | MIN | MAX |
| a | 8.00 | 7.90 | 8.30 |
| b | 1.75 | 1.65 | 1.85 |
| c (Note 2) | 3.50 | 3.45 | 3.55 |
| d | 4.00 | 3.90 | 4.10 |
| e | 2.00 | 1.95 | 2.05 |
| f (Note 2) | 2.00 | 1.95 | 2.05 |
| g | 1.50 | | 1.60 |
| h | 0.50 | 0.45 | 0.55 |

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

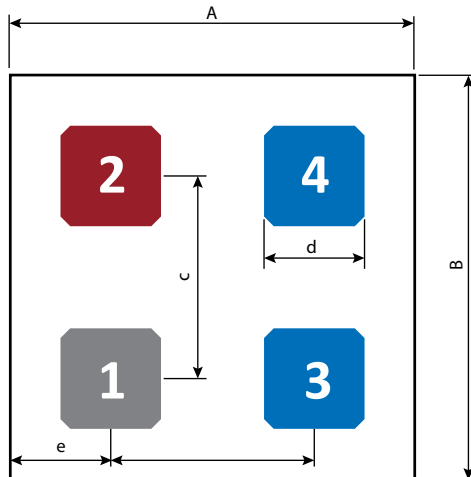
DIE MARKINGS



| Part Number | Laser Markings | |
|-------------|-----------------------|------------------------------|
| | Part # Marking Line 1 | Lot Date Code Marking Line 2 |
| EPC2121 | AK | YYY |

DIE OUTLINE

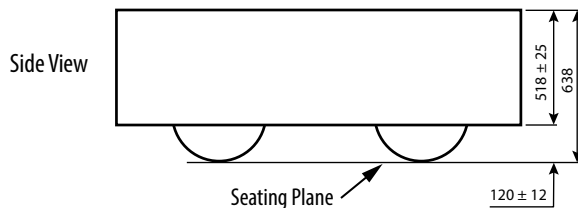
Solder Bump View



| DIM | MICROMETERS | | |
|----------|-------------|---------|-----|
| | MIN | Nominal | MAX |
| A | 870 | 900 | 930 |
| B | 870 | 900 | 930 |
| c | | 450 | |
| d | 205 | 225 | 245 |
| e | | 225 | |

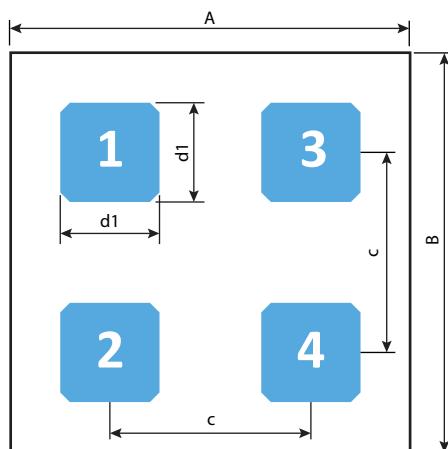
Pad 1 is Gate;
Pad 2 is Source;
Pad 3 is Drain 1;
Pad 4 is Drain 2

Note: Drain 1 and Drain 2 are interchangeable



RECOMMENDED LAND PATTERN

(units in μm)



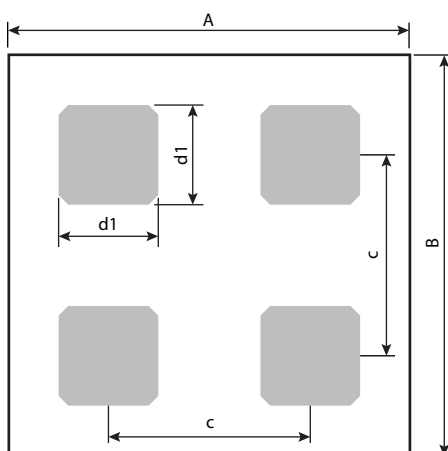
Land pattern is solder mask defined

| DIM | MICROMETERS |
|-----------|-------------|
| A | 900 |
| B | 900 |
| c | 450 |
| d1 | 205 |

Pad 1 is Gate;
Pad 2 is Source;
Pad 3 is Drain 1;
Pad 4 is Drain 2

RECOMMENDED STENCIL DRAWING

(measurements in μm)



| DIM | MICROMETERS |
|-----------|-------------|
| A | 900 |
| B | 900 |
| c | 450 |
| d1 | 205 |

Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, opening per drawing.

The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional resources available:

- Assembly resources – https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf
- Library of Altium footprints for production FETs and ICs – <https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip>
(for preliminary device Altium footprints, contact EPC)

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